



NES

NEW ENGLAND SEMICONDUCTOR

2N3738
2N3739*

*also available as
JAN, JANTX,
JANTXV

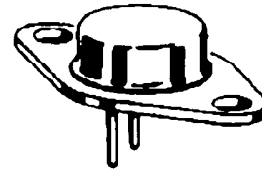
HIGH VOLTAGE SILICON POWER TRANSISTORS

...designed for high-speed switching, linear amplifier applications, high-voltage operational amplifiers, switching regulators, converters, inverters, deflection stages and high fidelity amplifiers.

- COLLECTOR -EMITTER SUSTAINING VOLTAGE
 $V_{CEO(sus)} = 225 \text{ Vdc @ } I_C = 5.0 \text{ mAdc (2N3738)}$
 $= 300 \text{ Vdc @ } I_C = 5.0 \text{ mAdc (2N3739)}$
- DC CURRENT GAIN --
 $h_{FE} = 40-200 @ I_C = 100 \text{ mAdc}$
- CURRENT-GAIN -- BANDWIDTH PRODUCT --
 $f_T = 10 \text{ MHz (Min) @ } I_C = 100 \text{ mAdc}$
- $I_{S/b}$ RATED TO 2.0 AMPERES

1.0 AMPERE
POWER TRANSISTORS
NPN SILICON

225, 300 VOLTS
20 WATTS

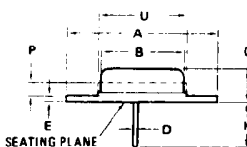
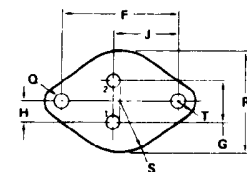


TO-66

MAXIMUM RATINGS

RATINGS	SYMBOL	2N3738	2N3739	UNITS
Collector-Emitter Voltage	V_{CEO}	225	300	Vdc
Collector-Base Voltage	V_{CB}	250	325	Vdc
Emitter-Base Voltage	V_{EB}	6.0		Vdc
Collector Current -- Continuous	I_C	1.0		Adc
-- Peak		2.0		
Base Current -- Continuous	I_B	0.50		Adc
-- Peak		1.0		
Total Power Dissipation @ $T_C = 25^\circ\text{C}$	P_D	20		W
Derate above 25°C		0.133		$\text{W}/^\circ\text{C}$
Operating & Storage Junction Temperature Range	T_J, T_{stg}	-55 to +200		$^\circ\text{C}$

MECHANICAL OUTLINE



PIN 1: BASE
PIN 2: EMITTER
CASE: COLLECTOR

DIM	MILLIMETER		INCHES	
	MIN	MAX	MIN	MAX
B	11.94	12.70	0.470	0.500
C	6.35	8.64	0.250	0.340
D	0.71	0.86	0.028	0.034
E	1.27	1.91	0.050	0.075
F	24.33	24.43	0.958	0.962
G	4.83	5.33	0.190	0.210
H	2.41	2.67	0.095	0.105
J	14.48	14.99	0.570	0.590
K	9.14	-	0.360	-
P	-	1.27	-	0.050
Q	3.61	3.86	0.142	0.152
S	-	8.89	-	0.350
T	-	3.68	-	0.145
U	-	15.75	-	0.620

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1-800-446-1158 / (978) 794-1666 / FAX: (978) 689-0803

T4-4.8-860-361 REV: --



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ELECTRICAL CHARACTERISTICS (T_C = 25°C unless otherwise noted)

Characteristics	Symbol	Min	Max	Unit
OFF CHARACTERISTICS				
Collector-Emitter Sustaining Voltage I _C = 5.0 mA _{dc} , I _B = 0	V _{CEO(sus)}	225 300		V _{dc}
		2N3738		
		2N3739		
Collector Cutoff Current V _{CE} = 125 V _{dc} , I _B = 0	I _{CEO}		0.25	mA _{dc}
V _{CE} = 200 V _{dc} , I _B = 0			0.25	
2N3738				
2N3739				
Emitter Cutoff Current V _{EB} = 6.0 V _{dc}	I _{EBO}		0.1	mA _{dc}
ON CHARACTERISTICS (1)				
DC Current Gain I _C = 50 mA _{dc} , V _{CE} = 10 V _{dc}	h _{FE}	30	-	
I _C = 100 mA _{dc} , V _{CE} = 10 V _{dc}		40	200	
I _C = 250 mA _{dc} , V _{CE} = 10 V _{dc}		25	-	
Collector-Emitter Saturation Voltage (1) I _C = 250 mA _{dc} , I _B = 25 mA _{dc}	V _{CE(sat)}		2.5	V _{dc}
Base-Emitter "ON" Voltage (1) I _C = 100 mA _{dc} , V _{CE} = 10 V _{dc}	V _{BE(on)}		1.0	V _{dc}
DYNAMIC CHARACTERISTICS				
Forward Current Transfer Ratio I _C = 100 mA _{dc} , V _{CE} = 20 V _{dc} , f = 1.0 kHz	h _{fe}	35		
Output Capacitance V _{CB} = 100 V _{dc} , I _E = 0, f = 100 kHz	C _{ob}		20	p ^F

(1) Pulse Test: Pulse Width ≤ 300μs, Duty Cycle ≤ 2.0%.

SX LEVEL RELIABILITY TESTING

100% SCREENING	GROUP A	GROUP B (Sample)	GROUP C (Sample)
Internal Visual	Visual and Mechanical	Solderability	Physical Dimensions
Temp Cycle	DC Static Tests 25°C	Temp Cycle	Thermal Shock
Thermal Response	DC Static Tests High Temp	Fine and Gross Leak	Terminal Strength
Constant	DC Static Tests Low Temp	Bond Strength	Hermetic Seal
Acceleration	Dynamic Tests @ 25°C	Intermittent Op Life	Moisture Resistance
PIND		Steady State Op life	Shock Test
Fine and Gross Leak		Thermal Resistance	Vibration Test
HTRB		Hi-Temp (non operating)	Constant Acceleration
Power Burn In			Salt Atmosphere
			Operation Life

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